

# 150V N-Channel Enhancement Mode Power MOSFET

# **Description**

WMB115N15HG2 uses Wayon's 2<sup>nd</sup> generation power trench MOSFET technology that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance. This device is well suited for high efficiency fast switching applications.

# PDFN5060-8L

### **Features**

- $V_{DS} = 150V$ ,  $I_D = 74A$ (Silicon Limited)  $R_{DS(on)} < 11.5m\Omega$  @  $V_{GS} = 10V$
- Low R<sub>DS(ON)</sub>
- 100% EAS Guaranteed
- High Speed Power Switching

## **Applications**

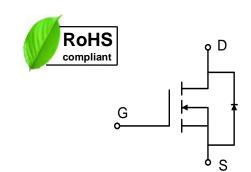
- Power Management Switches
- DC/DC Converter
- Synchronous Rectification in SMPS

# **Absolute Maximum Ratings**

Parameter		Symbol	Value	Unit	
Drain-Source Voltage		V <sub>DS</sub>	150	V	
Gate-Source Voltage		V <sub>GS</sub>	±20	V	
Continuous Proin Current4/Cilicon Limited	T <sub>C</sub> =25°C	I <sub>D</sub>	74		
Continuous Drain Current1(Silicon Limited)	T <sub>C</sub> =100°C		47	Α	
Continuous Drain Current¹(Package Limited)	T <sub>C</sub> =25°C		60		
Pulsed Drain Current <sup>2</sup>		I <sub>DM</sub>	250	Α	
Single Pulse Avalanche Energy <sup>3</sup>		EAS	320	mJ	
Total Power Dissipation <sup>4</sup>	T <sub>C</sub> =25°C	P <sub>D</sub>	114	W	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to+ 150	°C	

### **Thermal Characteristics**

Parameter	Symbol	Value	Unit
Thermal Resistance from Junction-to-Ambient <sup>1</sup>	ReJA	55	°C/W
Thermal Resistance from Junction-to-Case <sup>1</sup>	R <sub>0</sub> JC	1.1	°C/W





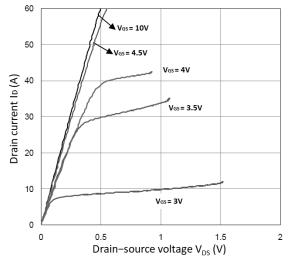
### Electrical Characteristics T<sub>c</sub> = 25°C, unless otherwise noted

Parameter		Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static Characteristics					ľ	l		
Drain-Source Breakdown Voltage		V <sub>(BR)DSS</sub>	$V_{GS} = 0V, I_D = 250\mu A$	150	-	-	V	
Gate-body Leakage Current		Igss	$V_{DS} = 0V$ , $V_{GS} = \pm 20V$	-	-	±100	nA	
Zero Gate Voltage Drain Current	T <sub>J</sub> =25°C	IDSS	V <sub>DS</sub> = 150V, V <sub>GS</sub> = 0V	-	-	1 100	μΑ	
Gate-Threshold Voltage		V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3	4	V	
Drain-Source On-Resistance	e <sup>2</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A	-	8.1	11.5	mΩ	
Forward Transconductance		<b>G</b> fs	V <sub>DS</sub> = 5V, I <sub>D</sub> = 20A	-	85	-	S	
Dynamic Characteristic	S	L	I		I	I		
Input Capacitance		Ciss	SS		3770	-	pF	
Output Capacitance  Reverse Transfer Capacitance		Coss	$V_{DS} = 75V$ , $V_{GS} = 0V$ , $f = 1MHz$	-	252	-		
		C <sub>rss</sub>		-	7.1	-		
Switching Characteristi	cs	l			l	I .		
Gate Resistance		Rg	$V_{DS} = 0V$ , $V_{GS} = 0V$ , $f = 1MHz$	-	2.6	-	Ω	
Total Gate Charge	Total Gate Charge		$V_{GS} = 4.5V, V_{DD} = 75V, I_{D} = 20A$	-	20.4	-		
Total Gate Charge		Qg		-	47	-	nC	
Gate-Source Charge Gate-Drain Charge		Qgs	$V_{GS} = 10V, V_{DD} = 75V, I_{D} = 20A$	-	10.8	-		
		$\mathbf{Q}_{\mathrm{gd}}$		-	4.9	-		
Turn-On Delay Time		t <sub>d(on)</sub>	)		17.5	-		
Rise Time Turn-Off Delay Time		tr	$V_{GS} = 10V, V_{DD} = 75V, R_G = 10\Omega,$ $I_{D} = 20A$	-	7.9	-	nS	
		t <sub>d(off)</sub>		-	28	-		
Fall Time		tf		-	10.3	-		
Drain-Source Body Dioc	de Charact	eristics		•	•			
Diode Forward Voltage <sup>2</sup>		V <sub>SD</sub>	I <sub>S</sub> = 20A, V <sub>GS</sub> = 0V	-	-	1.2	V	
Reverse Recovery Time		<b>t</b> rr	V <sub>R</sub> =75V, I <sub>F</sub> =20A,	-	60	-	ns	
Reverse Recovery Charge		Qrr	dl <sub>F</sub> /dt=100A/μs	-	150	-	nC	

### Notes:

- 1. The data tested by surface mounted on a 1 inch $^2$  FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq 300$ us , duty cycle  $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is  $\ensuremath{V_{DD}}\text{=}25\ensuremath{V,V_{GS}}\text{=}10\ensuremath{V,L}\text{=}0.4\text{mH}$
- 4.The power dissipation is limited by 150  $^{\circ}\text{C}\,$  junction temperature
- 5. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.





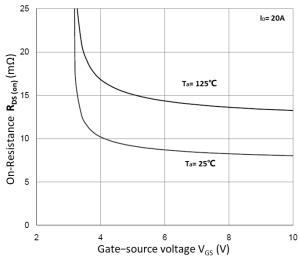
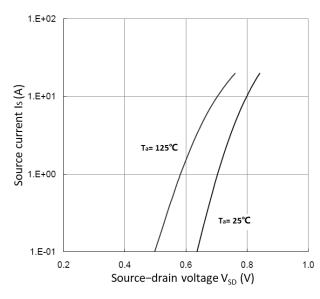


Figure 1. Output Characteristics

Figure 2. R<sub>DS(on)</sub> vs. V<sub>GS</sub>



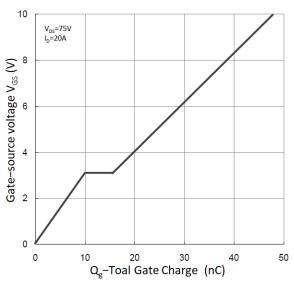
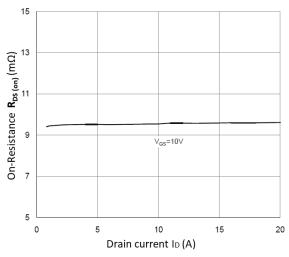


Figure 3. Forward Characteristics of Reverse

Figure 4. Gate Charge Characteristics



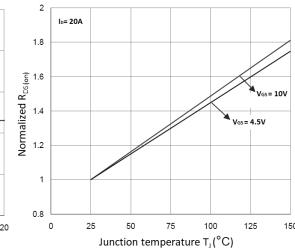


Figure 5. RDS(ON) vs. ID

Figure 6. Normalized R<sub>DS(on)</sub> vs. T<sub>J</sub>



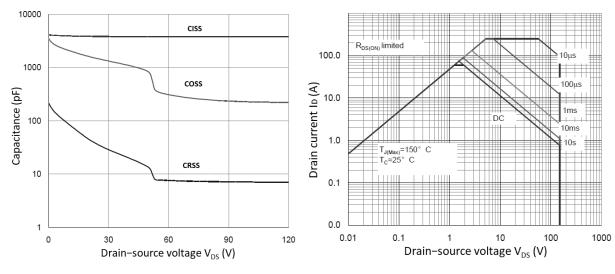


Figure 7. Capacitance Characteristics

Figure 8. Safe Operating Area

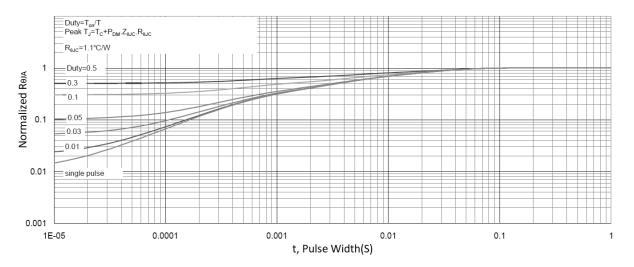


Figure 9. Normalized Maximum Transient Thermal Impedance

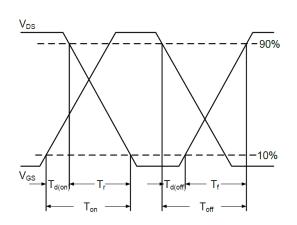


Figure 10.Switching Time Waveform

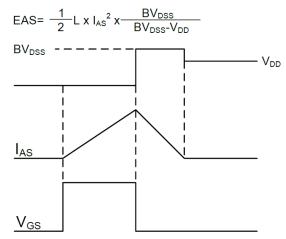
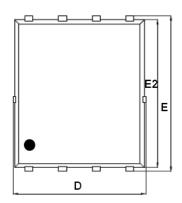


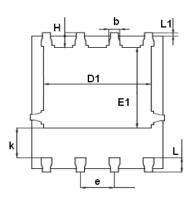
Figure 11. Unclamped Inductive Switching

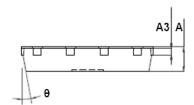
Waveform



### **Mechanical Dimensions for PDFN5060-8L**







### **COMMON DIMENSIONS**

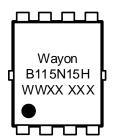
SYMBOL	MM			
	MIN	MAX		
Α	0.90	1.20		
А3	0.15	0.35		
D	4.80	5.40		
E	5.90	6.35		
D1	3.61	4.31		
E1	3.30	3.92		
E2	5.65	6.06		
k	1.10	-		
b	0.30	0.51		
е	1.27BSC			
L	0.38	0.71		
L1	0.05	0.36		
Н	0.38	0.61		
θ	0°	12°		



### **Ordering Information**

Part	Package	Marking	Packing method	
WMB115N15HG2	PDFN5060-8L	B115N15H	Tape and Reel	

### **Marking Information**



B115N15H= Device code
WWXX XXX= Date code

### **Contact Information.**

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For additional information, please contact your local Sales Representative.

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